

Search Notes

Application/Control No.

10/601,872

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

CHOI ET AL.

Art Unit

1745

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 429 | 27 | 2/14/2006 | DWY |
| 429 | 40 | 2/14/2006 | DWY |
| 429 | 42 | 2/14/2006 | DWY |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|------|-----------|------|
| EAST | 2/14/2006 | DWY |
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